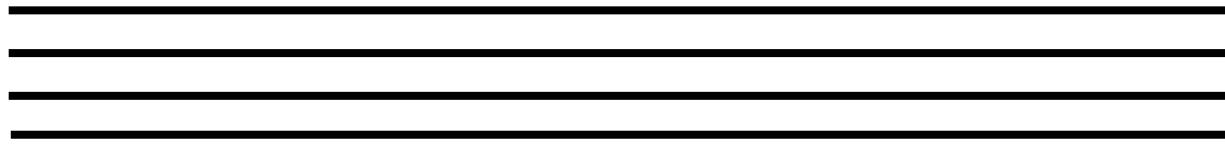

Overview of Phase Contrast & High resolution TEM

Lecture 14

High-resolution EM

general idea

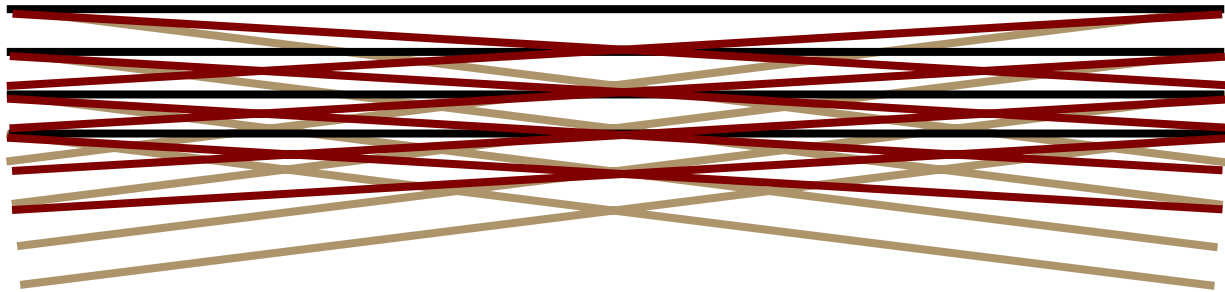
Incident
electron
wave



Sample
(very thin!)



Transmitted
&
Diffracted
waves



Transmitted & diffracted waves each have a different phase

Result is an interference pattern - our 'phase contrast' or HREM image

High-resolution EM

general idea

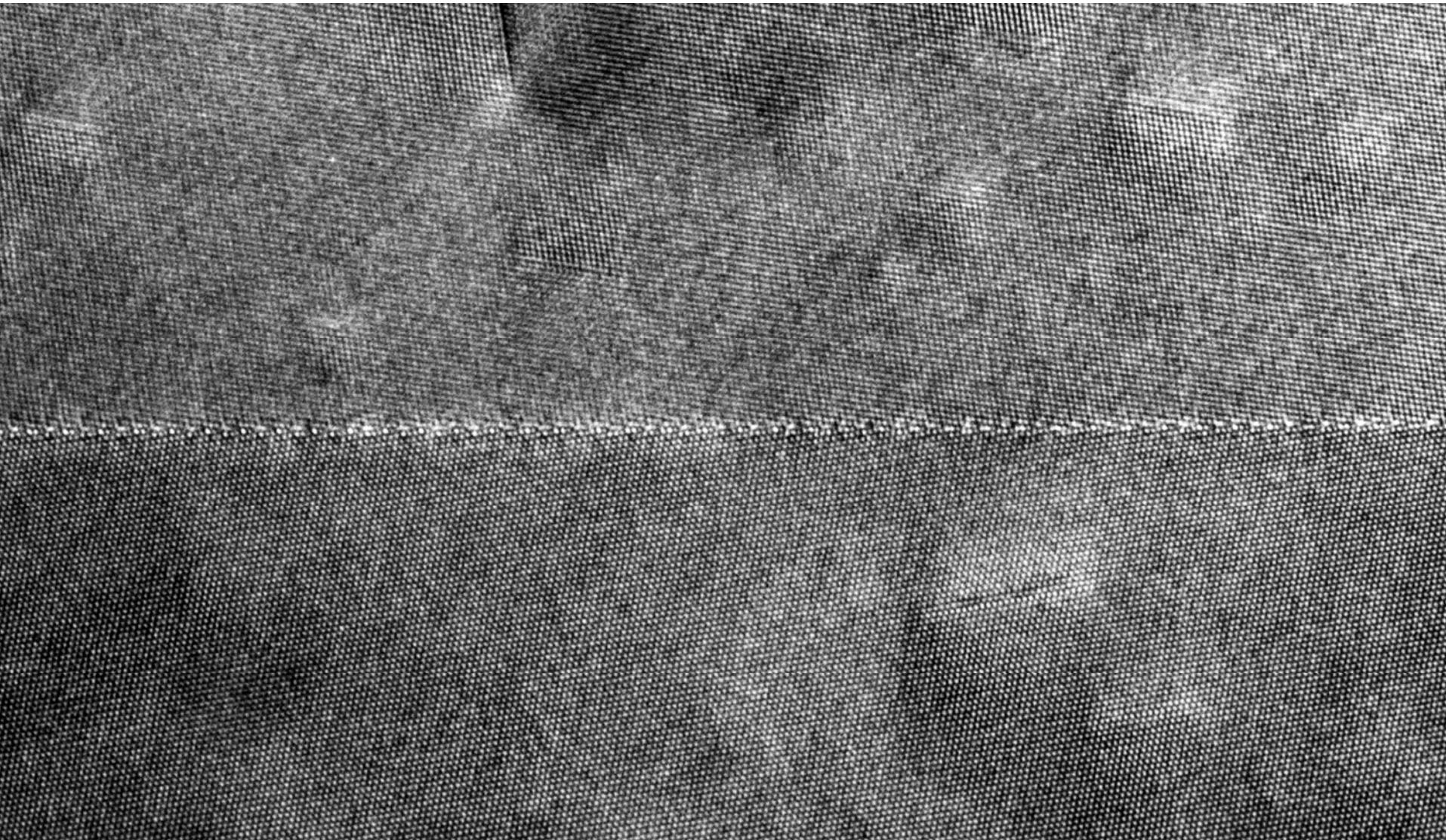


Image courtesy U. Dahmen, NCEM, LBNL

High-resolution EM

general idea

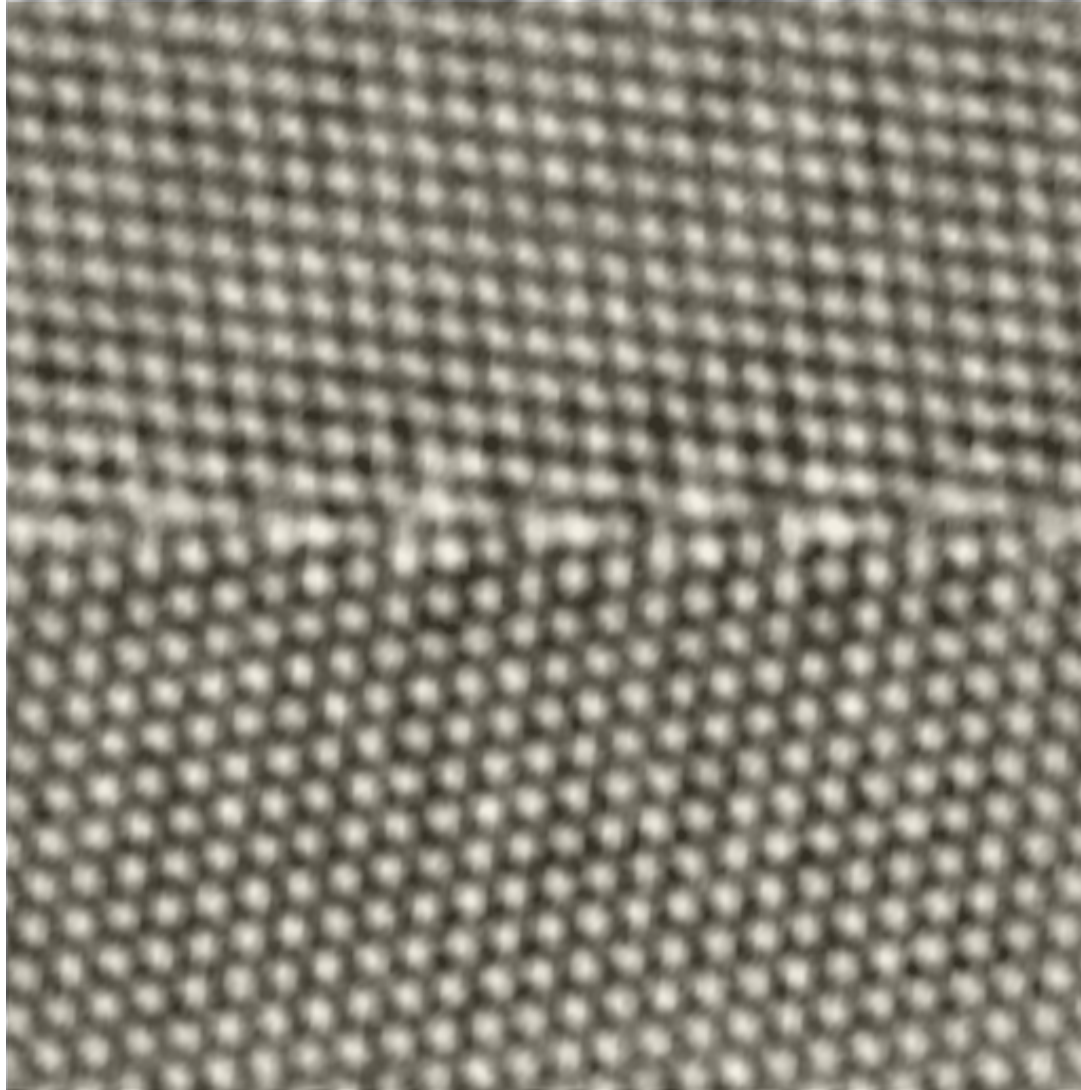
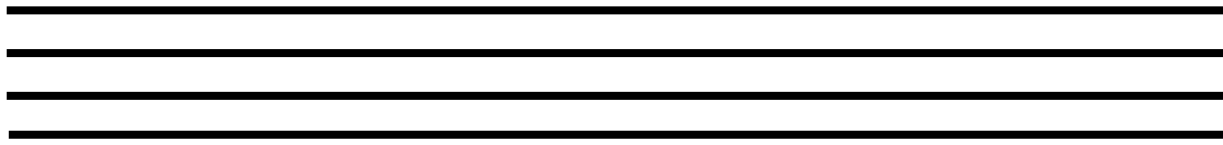


Image courtesy U. Dahmen, NCEM, LBNL

High-resolution EM

general idea

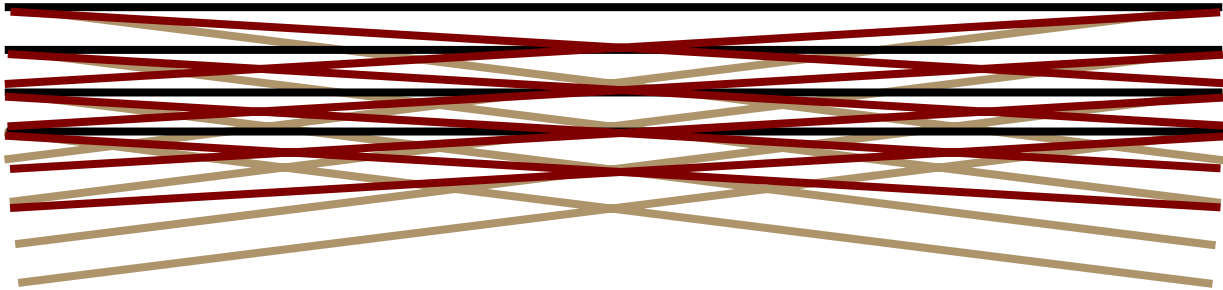
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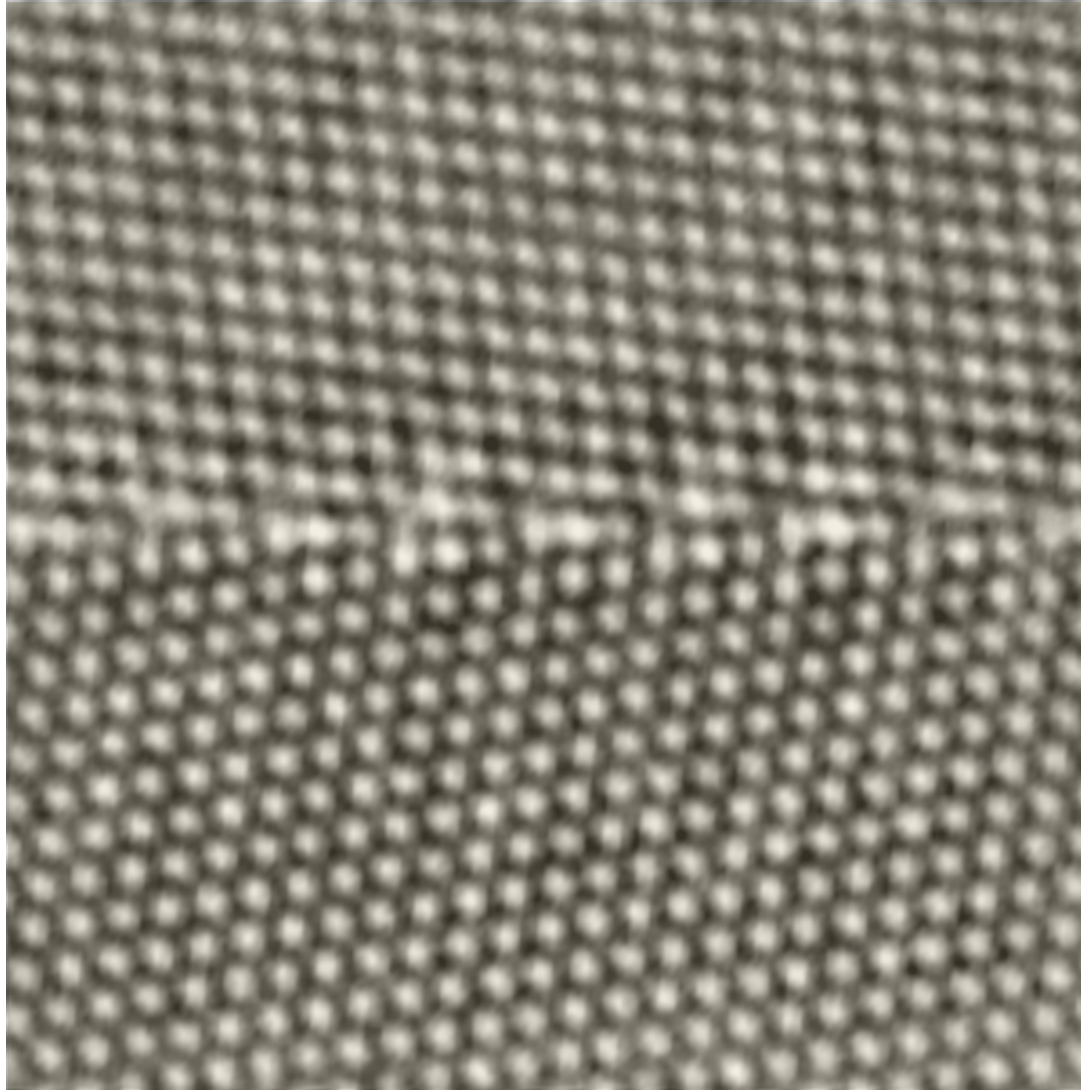


Image courtesy U. Dahmen, NCEM, LBNL

High-resolution EM

general idea

Why are the phases different?

Transmitted & diffracted waves are allowed wave functions in the crystal

- Together they form the “Exit Wave” which leaves the crystal

They solve Schrödinger’s Equation

$$\nabla^2 \psi(\vec{r}) + \frac{8\pi m e}{h^2} [E + V(\vec{r})] \psi(\vec{r}) = 0$$

Solutions are Bloch Waves:

$$b^{(j)}(\mathbf{k}^{(j)}, \vec{r}) = \sum_{\mathbf{g}} \underbrace{C_{\mathbf{g}}^{(j)}}_{\text{Amplitude term}} \underbrace{\exp[2\pi i (\mathbf{k}^{(j)} + \mathbf{g}) \cdot \vec{r}]}_{\text{Phase term}}$$

Amplitude term

Phase term

High-resolution EM

general idea

Looking at these Bloch waves:

$$\mathbf{b}^{(j)}(\vec{\mathbf{r}}) = \sum_{\mathbf{g}} \mathbf{C}_{\mathbf{g}}^{(j)} \exp \left[\underline{2\pi i (\mathbf{k}^{(j)} + \mathbf{g}) \cdot \vec{\mathbf{r}}} \right]$$

Phase term has to do with the strength & spacing of the periodic potential of the lattice along a given direction in the crystal (\mathbf{g})

Different diffracted waves have different phase shifts

The total “Exit Wave” is thus the sum over all of the Bloch waves

$$\Psi_{\text{total}} = \sum_{j=1}^n \mathcal{A}^{(j)} \psi^{(j)} = \sum_{j=1}^n \mathcal{A}^{(j)} \mathbf{b}(\mathbf{k}^{(j)}, \mathbf{r})$$

High-resolution EM

general idea

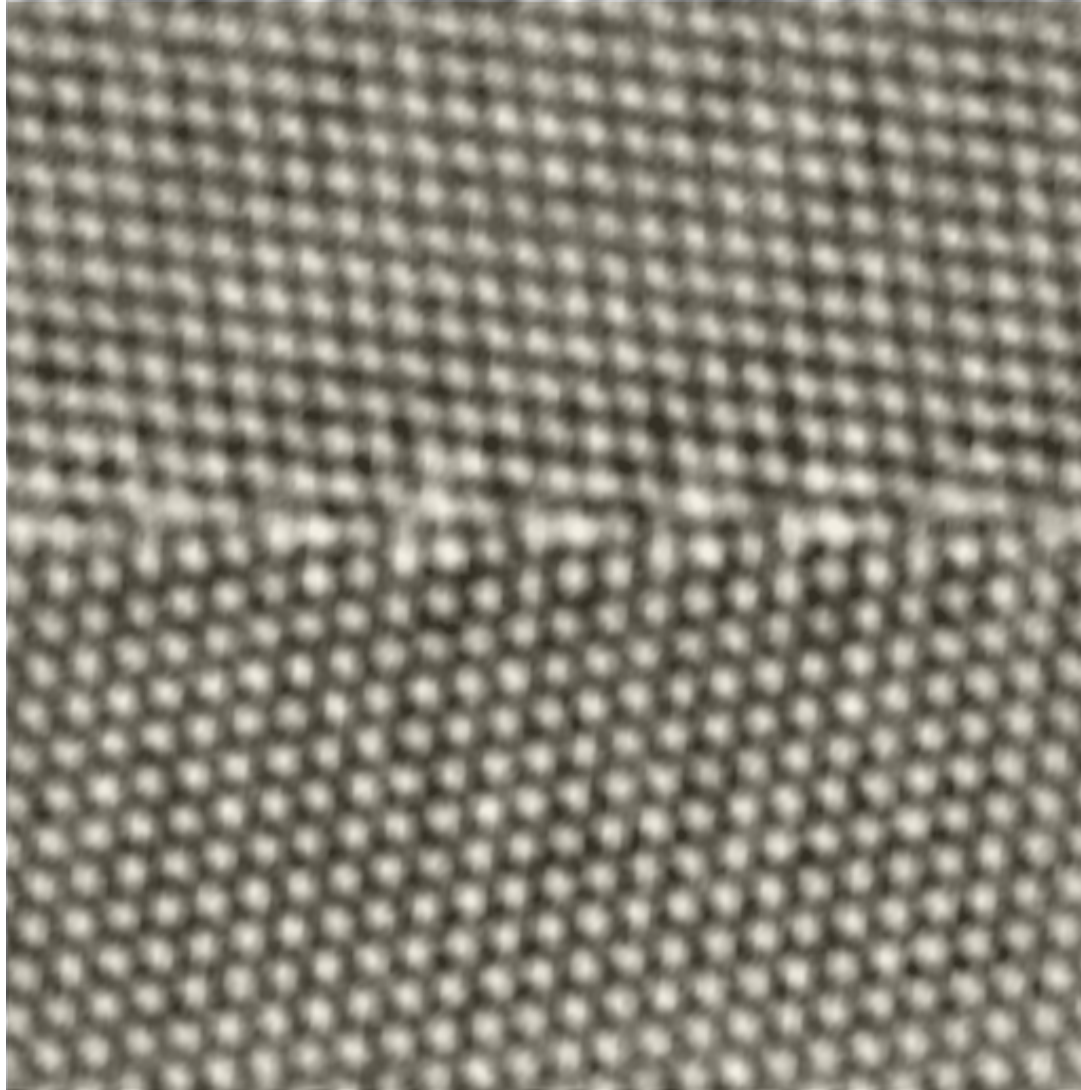
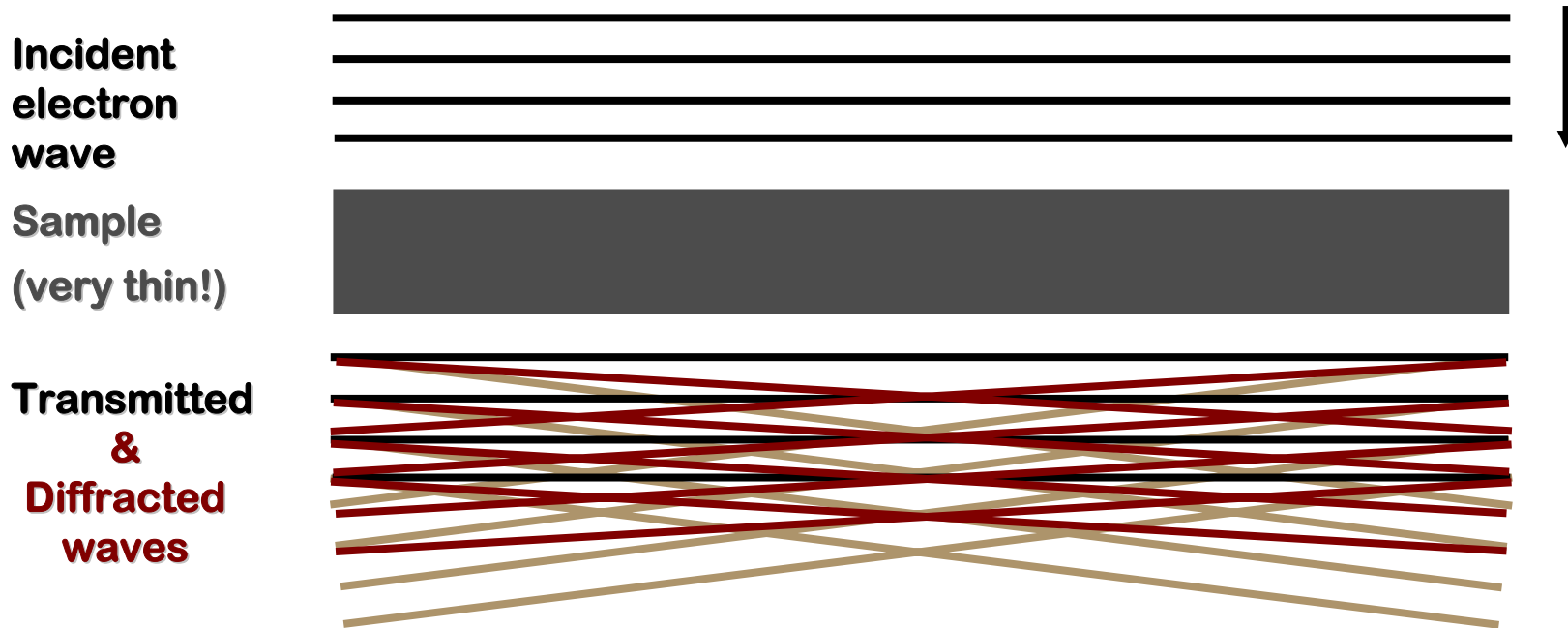


Image courtesy U. Dahmen, NCEM, LBNL

High-resolution EM

general idea



So, appears “simple” enough ...

- (1) Calculate the phase differences for the different diffracted waves
- (2) Create an interference pattern from the overlap of these phases in two-dimensions

High-resolution EM

general idea

Not even this “simple”

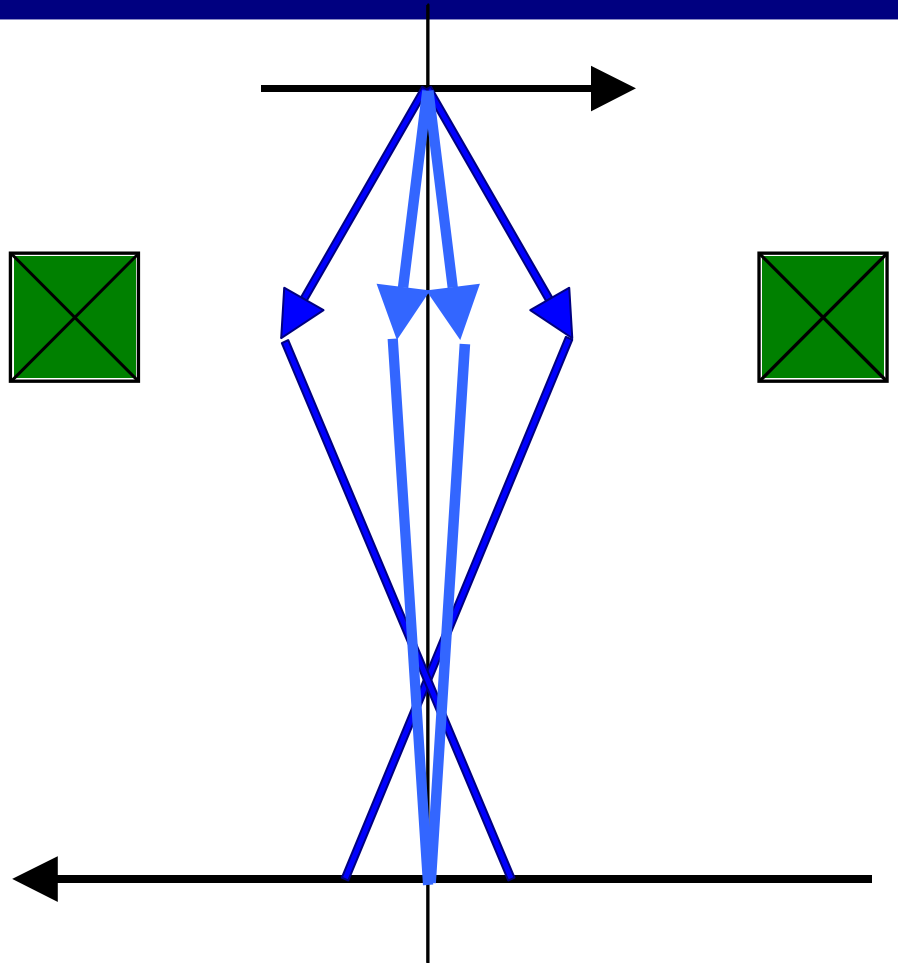
The TEM has very poor lenses

- Spherical aberration in particular

This aberration causes diffracted waves to be ‘phase shifted’ by the objective lens

- Complex dependence on wavelength, C_s , diffraction vector and defocus
- Magnitude of shift varies with distance from optic axis
 - And thus diffraction angle
 - Thus each diffracted wave undergoes a different phase shift

Complicates image interpretation

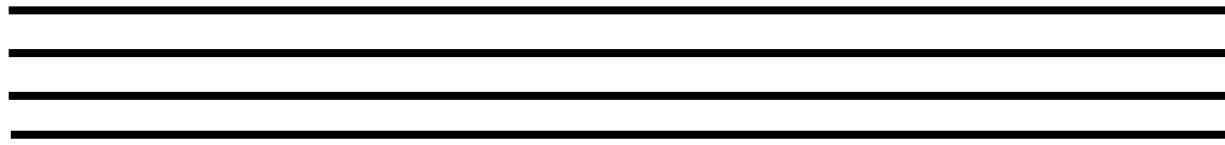


Spherical aberration

High-resolution EM

general idea

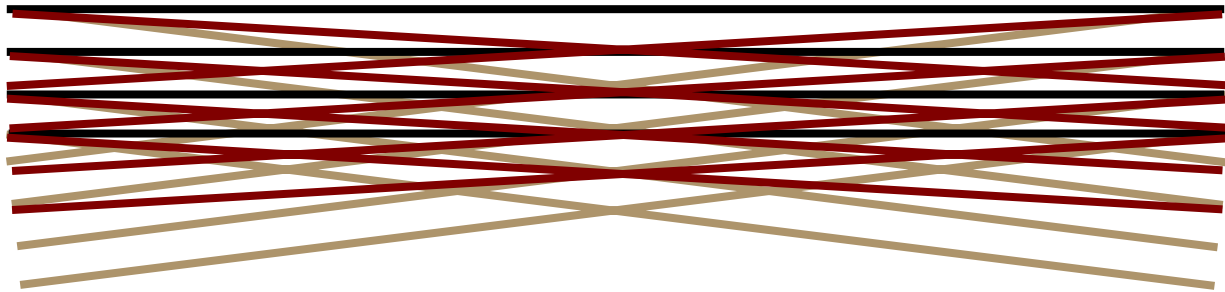
Incident
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wave



Sample
(very thin!)



Transmitted
&
Diffracted
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Returning to this picture

This means that the phases of the diffracted waves are
changed by the objective lens focus

High-resolution EM

general idea

Not even this “simple”

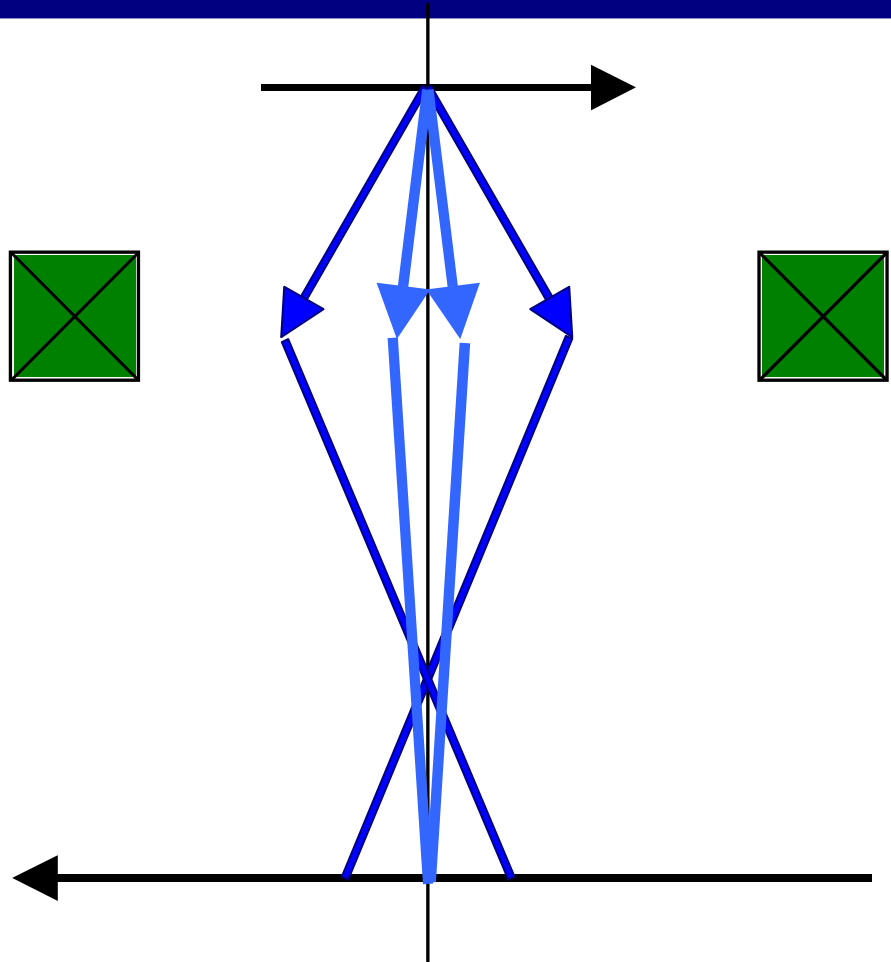
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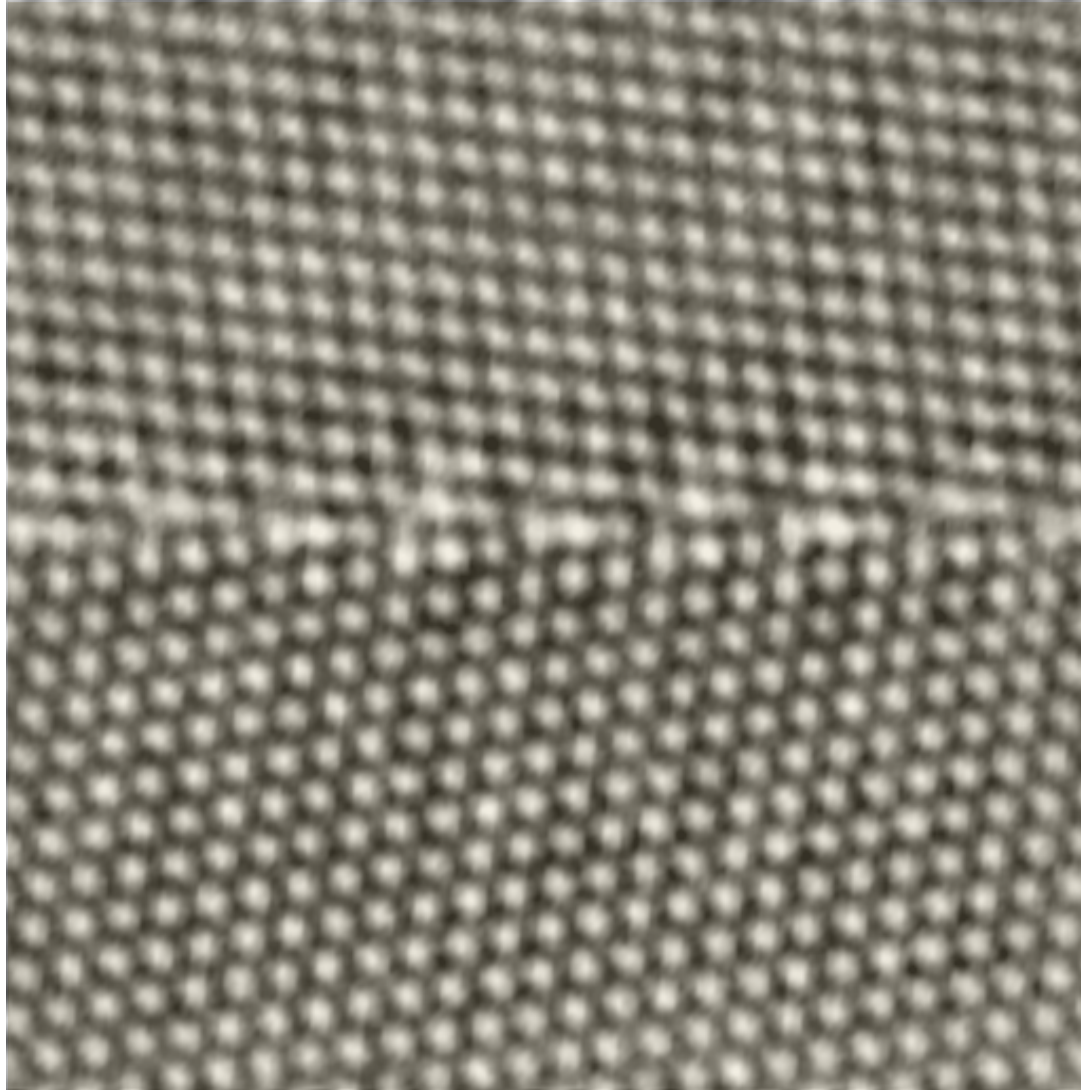
Complicates image interpretation



Spherical aberration

High-resolution EM

general idea



High-resolution EM

general idea

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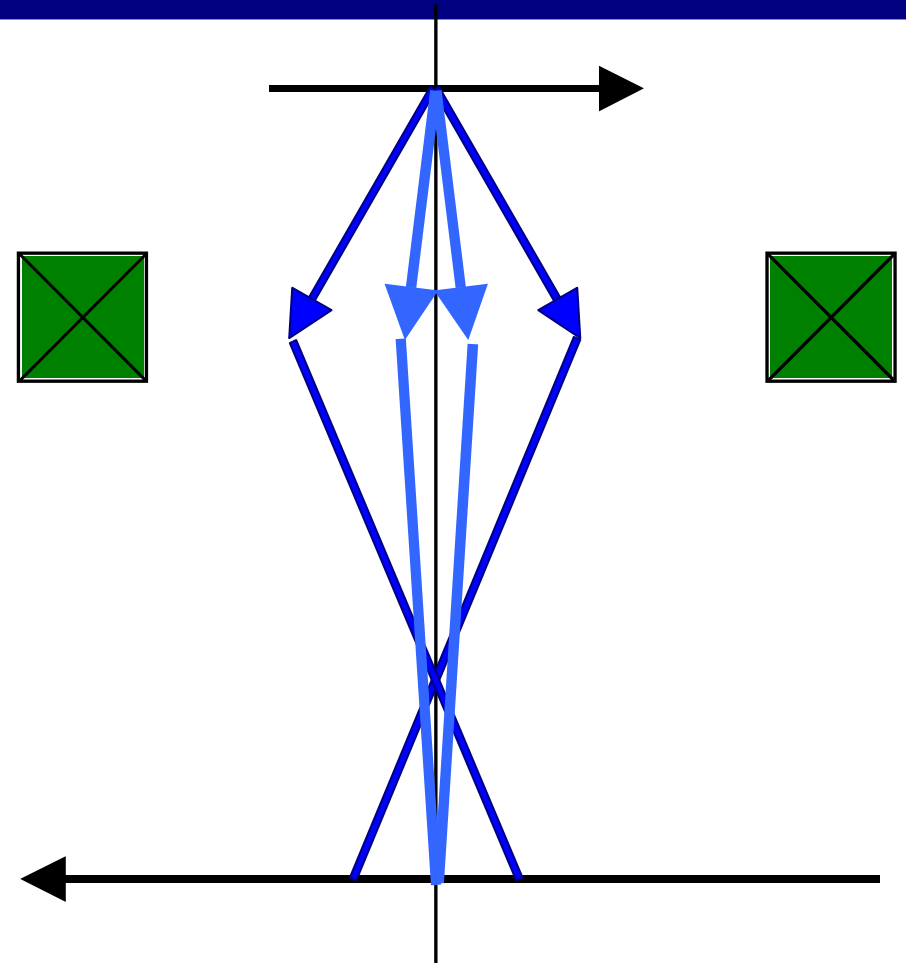
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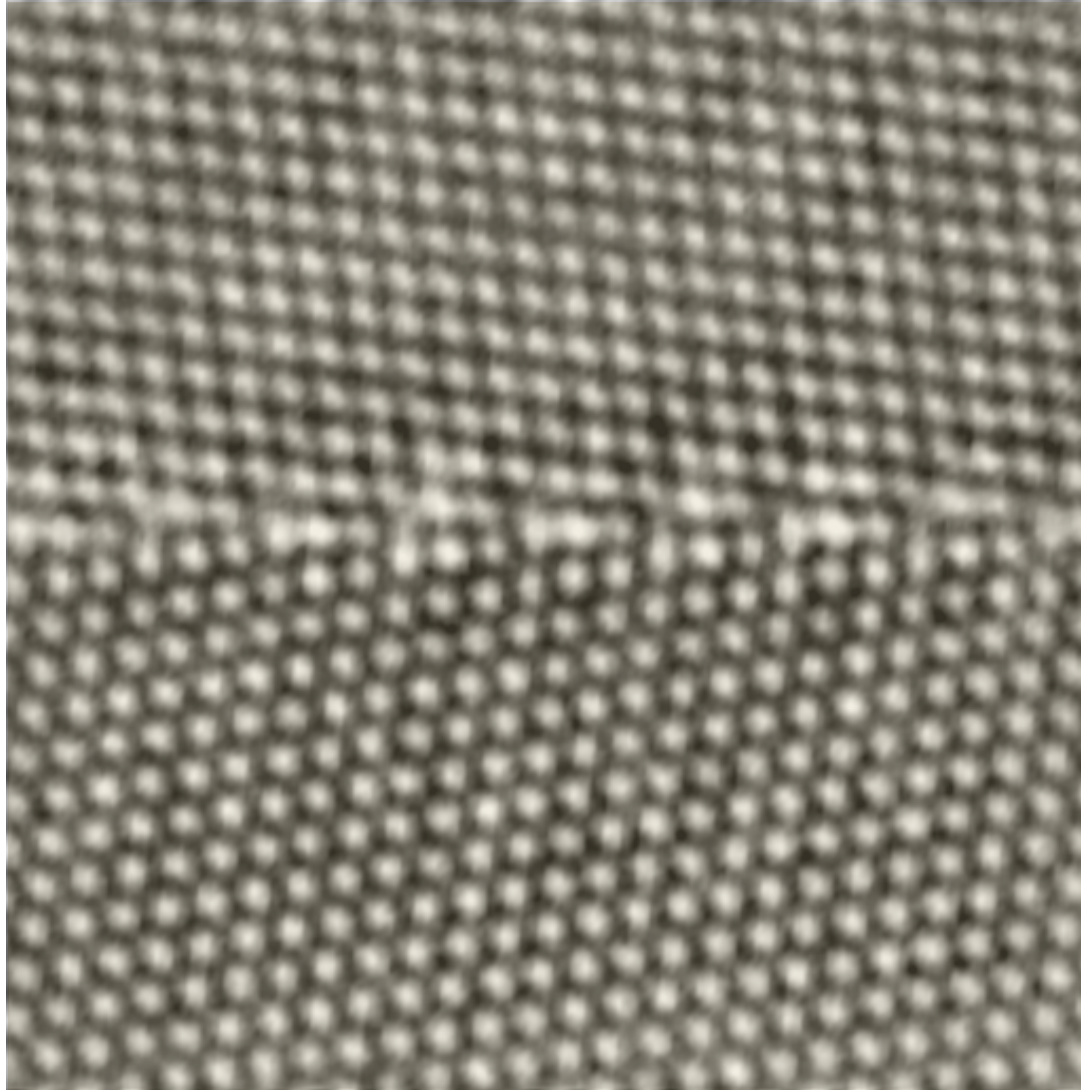


Image courtesy U. Dahmen, NCEM, LBNL

High-resolution EM

general idea

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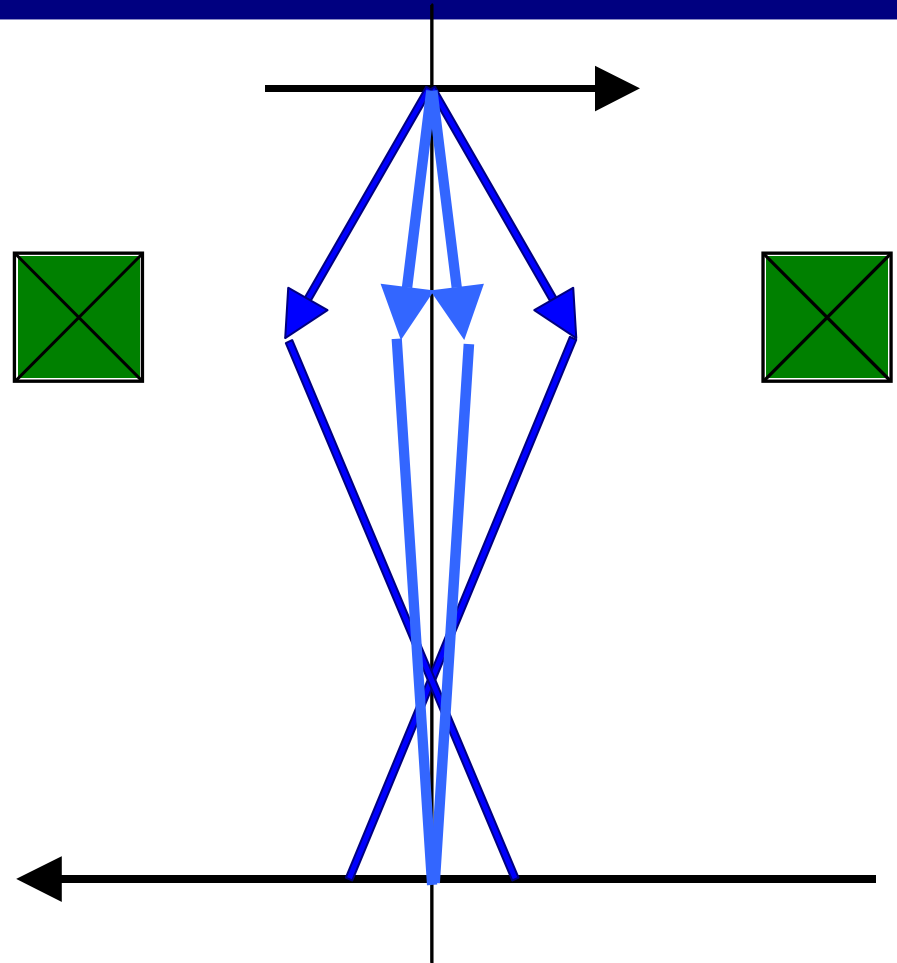
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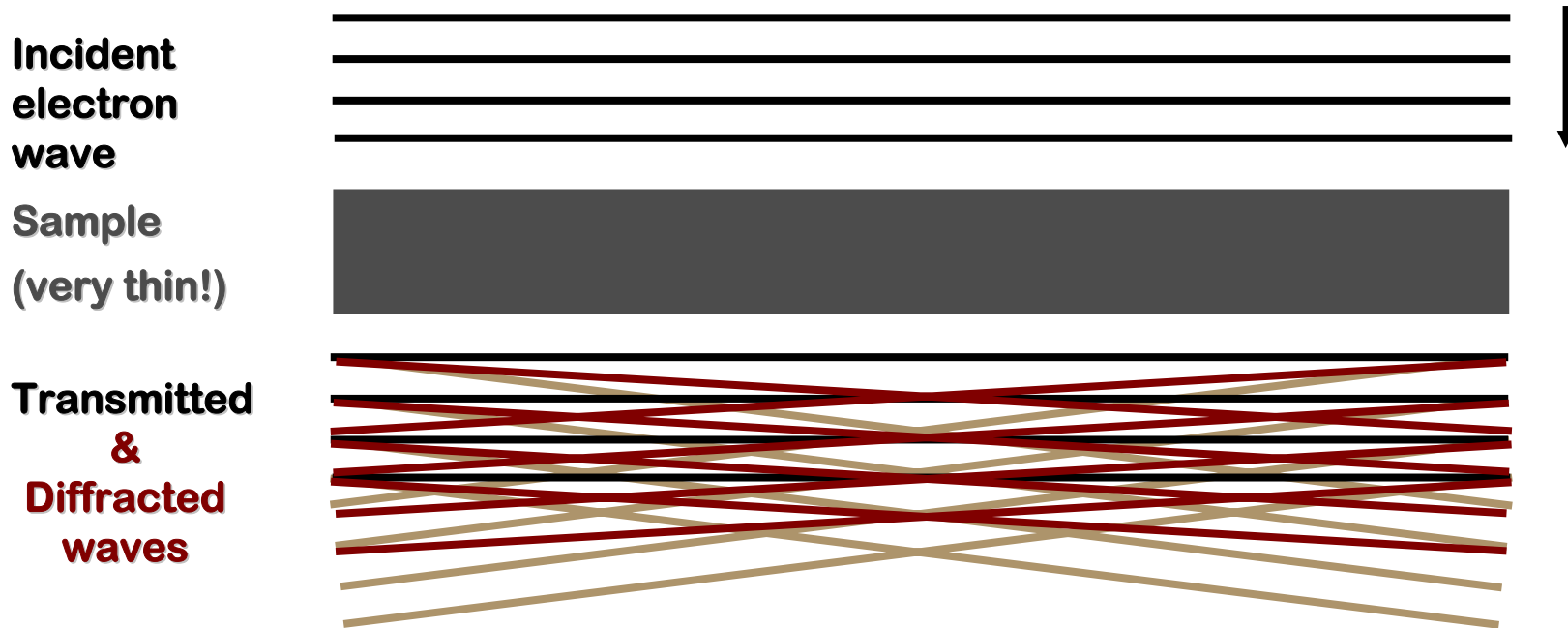
Complicates image interpretation



Spherical aberration

High-resolution EM

general idea



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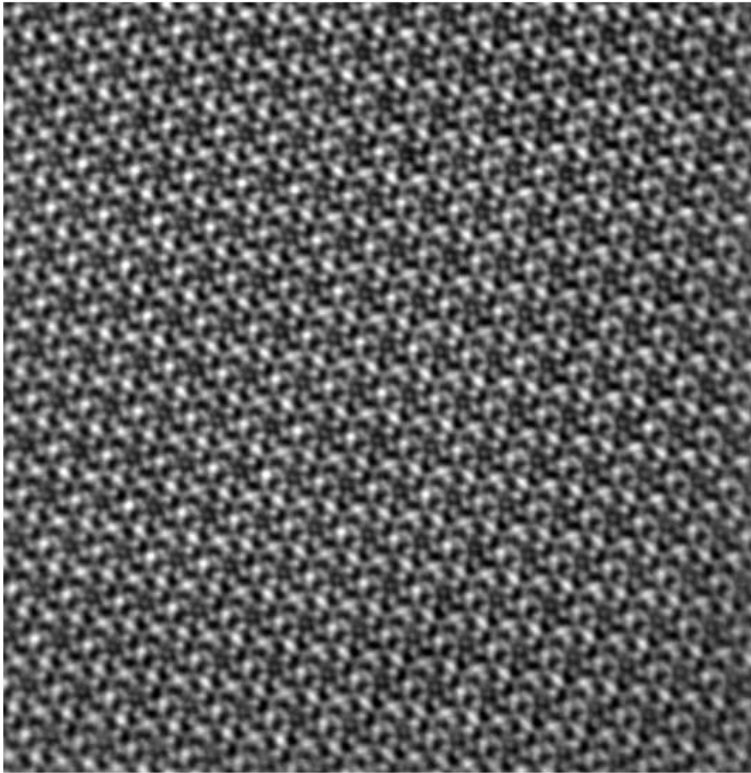
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High-resolution EM

general idea

Thus, the image you get **STRONGLY DEPENDS ON THE FOCUS CONDITION**

A single HREM image



The 'unscrambled' exit wave

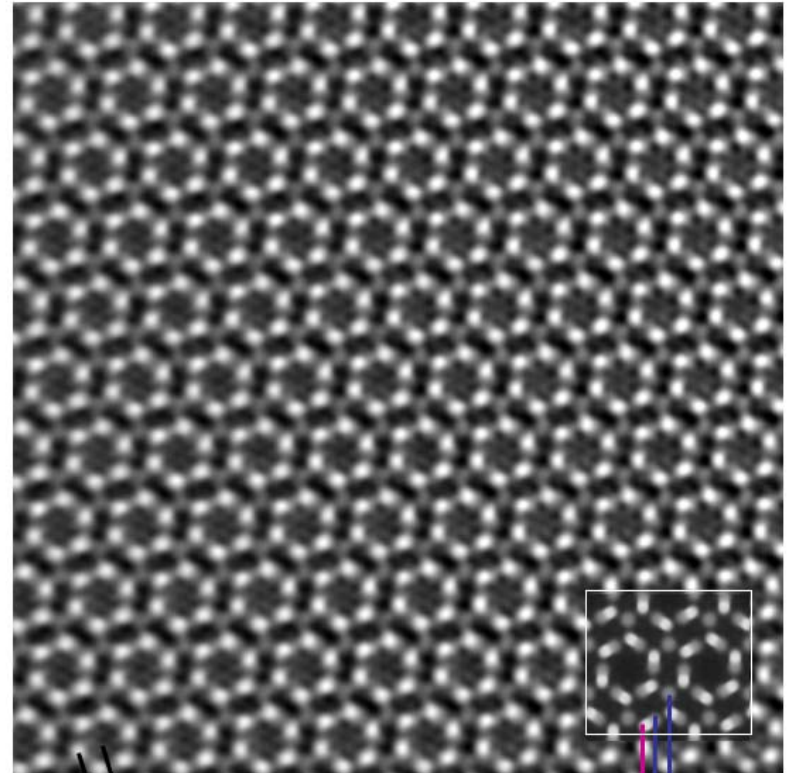


Image courtesy C. Kisielowski, NCEM, LBNL

0.18 nm

Simulation: Si N_{1,2}